

A Meta-Stacked Software Bug Prognosticator Classifier

Ajay Kumar Shrivastava*1, Dr. Ekbal Rashid² *1M.Tech Research Scholar, Jharkhand Rai University, Ranchi, Jharkhand, India ²Department of CSE, Aurora's Technological and Research Institute, Uppal, Hyderabad, Telangana, India

ABSTRACT

Predicting defects defines the proactive process of classifying the defects that can be found in entire software's content, within and cross-project codes for producing high quality product with optimized cost. Error prediction in open source software is more crucial due to its inherent complexity and the large repository of contributors. In this paper we present the meta-stacked regression model (MSRM) which improvises the Rayleigh Probabilistic distribution for feature selection estimates. Firstly, a heuristic bug mining approach is adopted to mine the parameters reported by developers and contributors of various Open source projects (Bugzilla, Eclipse, Mozilla) activity logs. In the second part, Stacked Regression is compared to Neural Networks and Linear Support Vector Machine models in terms of the bug prediction performance with Feature importance and Correlation amongst parameters. The results show that the ensemble based Stacked regression has better precision and F-measure compared to simple machine learning models. The MSRM model accurately predicts and classifies bugs with accuracy of 96.8% and reduces the impact of false positives by recall of 71.2%. **Keywords:** Stacked Regression, Bug Prediction, Cost Estimation, Rayleigh defect density, Software Project Bugs

I. INTRODUCTION

The occurrence of bugs is a deterrent in any software project cost estimation and directly affects the quality and success of any software management. It can affect macroscopic elements like resource allocation, project planning and bidding, as well as micro-level phase wise design and execution hence bug estimation at an early stage of software testing has led to extensive research efforts. Bugs can reduce the reliability of a software system affecting its estimation and model accuracy. Boehm's constructive cost model COCOMO and COCOMO II [3], Albrecht's function point method [2] and Putnam's software life cycle management (SLIM) [15] are the initial algorithmic estimation methods which were used for software estimation by Constructive Cost Model is by far the most commonly used because of its simplicity for estimating the effort in person-month for a project at different stages.

The most fundamental calculation in the COCOMO model is the use of the Effort Equation to estimate the number of Person-Months required developing a project. The other results including the estimates for Requirements and Maintenance are derived from LOC and effort equation. However, the model estimates the cost and schedule of the project, starting from the design phase and till the end of integration phase. For the remaining phases a separate estimation model should be used. Also, since the cost estimation may vary due to changes in the requirements, staff size, and environment in which the software is being developed. This paper hence focuses on feature selection of reported bug attributes by proposing an Integrated Meta-Stacked Regression Model (MSRM) improvising cost of Bug estimation and prediction accuracy.

The remainder of this paper is organized as follows: Sect. II discusses about the related literature review and its shortcomings. Section III discusses about the methods involved in implementing the various metaclassifiers.

Section IV discusses the proposed MSRM process flow on various classifiers. Section V discusses the results and paves way for further research.

II. RELATED WORK

Barry Boehm et.al [3](2000) addressed on an overview of a variety of software estimation models indicating that neural-net and dynamics-based techniques are less mature than the other classes of techniques and are challenged by the rapid changes in software technology. The key to arriving at sound estimates is to have a grasp of the factors which are driving the costs of the project at hand to support the project planning and control functions performed by the management.

S.Wang et.al [2](2016) proposed to bridge the gap between programs' semantics and defect prediction features by representation-learning algorithm. Deep Belief Network (DBN) was adopted to learn semantic features from token vectors extracted from programs' Abstract Syntax Trees (ASTs) and evaluated on ten open source projects. Results showed improvement in WPDP 14.7% in precision, 11.5% in recall, and 14.2% in F1. For CPDP, the semantic features based approach outperforms the state-of-the-art technique TCA+ with traditional features by 8.9% in F1 score.

The first contribution of our work is to find the set of priority attributes that affect the cost of bug estimation the most. Second is to evaluate the stacked classifiers (Regression, Neural Network, Linear SVM) with density distribution in terms of prediction accuracy and F1 score.

III. METHODOLOGY

Feature selection aims to find a Q-dimensional subset of features, Set Q, $(Q \in F)$ that optimizes classifier performance and optionally minimizes the feature set size. The primary reasons to use feature selection are that it enables the machine learning algorithm to train faster, improves the accuracy of a model with the right subset and it substantially reduces over fitting. With a carefully chosen set $A \subset R$, we can classify a new data point $x \in R$ d by checking whether $f(x) \in A$.

3.1 Logistic Regression Model

The regression model considered for classification of bug occurrence can be written in the form For n independent pairs (x_i, y_i), i=1,2,.. n where $x'_i = (x_{0i}, x_{1i}, ..., x_{ni})$. For the outcome Y_i, the logistic regression model assumes that $P(Y_{i=1} \text{ for } x_i) = \mu(x_i)$ (i) where $\mu(x_i) = e^{g(xi)} / (1 + e^{g(xi)})$ with $g(x_i) = x'_i \beta$(ii) The maximum likelihood is obtained for parameter estimates and the fitted values are specified as

 $\mu'(x_i) = \mu(x_i, f_i)$ i.e. logit[$\mu(x)$]= x' f.....(iii)

3.2 Linear Support Vector Model

Linear Classifiers define the margin as the width that the boundary could be increased by before hitting a datapoint. Support Vectors are those data points that the margin pushes up against linear classifier with the maximum margin. This is called LSVM.

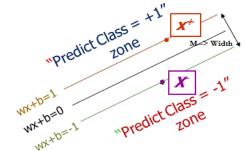


Figure 1. Linear Support Vectors as function of weight and bias The linear objective is expressed as

\mathcal{F}	$(\mathbf{x}_i, \mathbf{x}_j) = \mathbf{x}_i^T \mathbf{x}_j$	(iv)

The corresponding goal of weights and bias is given as $\mathbf{w} = \sum \alpha_i y_i \mathbf{x}_i$; $b = y_{k-} \mathbf{w}^T \mathbf{x}_k$(v) for any \mathbf{x}_k such that $\alpha_k \neq 0$. Here, each non-zero α_i indicates that corresponding \mathbf{x}_i is a support vector and classifying function will have the form

 $\mathcal{F}(\mathbf{x}) = \Sigma \alpha_i y_i \mathbf{x} \mathbf{x} + b....(vi)$

3.3 Radial Basis Function Neural network Model

The objective of Neural system is to find a progression of weights that will give important values in the yield when determined particular cases of its information. Each node in hidden layer gain input from the input layer, which are multiplexed with proper weights and reduced.

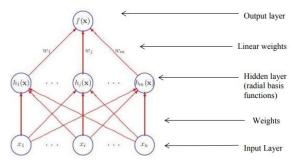


Figure 2. The mathematical analogy of ANN with synaptic structure of Neural Systems with output f(x)

3.4 Rayleigh's Density Distribution

The Rayleigh distribution[6] is a special case of the Weibull distribution, which provides a population model useful in several areas of statistics, including life testing and reliability study. Rayleigh distribution RD (\emptyset) is employed in parameter estimation using different types of censoring and non-censoring data and written as :-

Probability Distribution Function (PDF)

$$= 2 * \emptyset_x * e^{-\emptyset x^2} \text{ where } x > 0 \text{ and } \emptyset > 0.....(vii)$$

- Also Cumulative Distribution Function (CDF)
- $= 1 e^{-\emptyset x^2}$(viii)

IV. PROPOSED FRAMEWORK

In this paper the following steps were taken in the process of model building of MSRM :-

1) Data Extraction

The bug reports of different products of Eclipse, Mozilla and Bugzilla [5]open source software were retrieved from the CVS repository and saved in .csv format from source : http://bugzilla.mozilla.org

2) Data Pre-Processing & Preparation

Remove missing and Noisy data by setting all non zero value to 1 for depends on and duplicate count attributes. Divide the Dataset into Training data for Model creation and testing data for validation (60:40).

ed Hat Bugzilla – Bug 1425569		gcc: internal compiler error: Segmentation fault	Last modified: 2017-02-21 13:45:41 E				
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Bug 1425569 - gcc: internal co	mpiler error: Segmentatio	on fault					
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Product: Fedora Component: gcc (Show of	her bugs)	See Also:					
Version: rawhide Hardware: Unspecified I	Jnspecified	Fixed In Version: Doc Type: If docs needed, set a value					
Priority unspecified 5 Target Milestone:	Severity unspecified	Doc Text: Clone Of: Environment:					
Target Release: Assigned To: Jakub Jelinel QA Contact: Fedora Extra		Last Closed: 2017-02-21 13:45:41 EST					

Figure 3. A Sample Bug report for Open Office Project with BugID 1425569

3) Modeling

Build three models based on LSVM, RBNN classifiers and Regression model.

Calculate the summary weight of bug attributes by using information gain criteria. Train the Model by using most relevant twelve attributes to predict and the bug severity.

Apply Rayleigh probability density to predict defect density for different phases of project life cycle.

4) Testing and Validation

Test the model for remaining dataset. Evaluate and access the performance of prediction models.

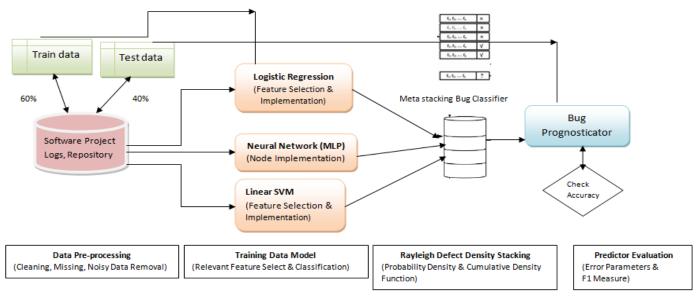


Figure 4. Overview of our proposed MSRM for defect prediction

Several experiments were conducted by recording the bug repository to study the performance of the proposed stacked model in comparison with existing classifiers. The experiments were run on a 2.5GHz i5-3210M machine with 4GB RAM.

To measure defect prediction results, we use four Evaluation metrics: Correlation, Precision, Recall, and F1score^[3].

Pearson's Correlation: It is used as a measure for quantifying linear dependence between two continuous variables X and Y. Its value varies from -1 to +1. Pearson's correlation is given as:

F-measure: Weighted (by class size) average F-measure was obtained from the classification using feature subset with the same three classifiers as above. It describes the Harmonic mean of Precision and Recall.

The general formula for positive real β is given by;

$$F_{\beta} = (1 + \beta^2) \times \frac{\operatorname{Precision} \times recall}{(\beta^2 \operatorname{Precision}) \times recall} \dots (\mathbf{x})$$

$$precision = \frac{TP}{TP + FP}$$
(xi)

$$recall = \frac{TP}{TP + FN}$$
(xii)

Here Precision is the ratio of all relevant correctly classified bugs to all retrieved bugs.

Recall is measured as the fraction of relevant items retrieved out of all relevant items including False data not correctly classified.

V. RESULTS AND DISCUSSION

The features are filtered according to the importance derived from the feature importance graph of LVSM. The positive and negative values in the graph show the role of feature in classifying positive and negative values. Therefore we select the extremities of the features for both the classes in case of Linear SVM.

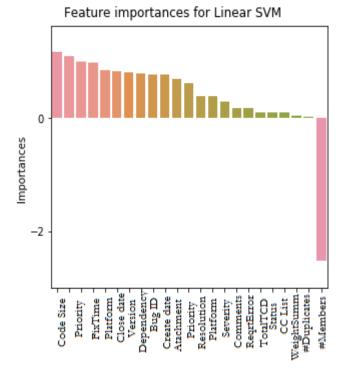


Figure 5. Bug Attributes Selected by Feature Importance Graph

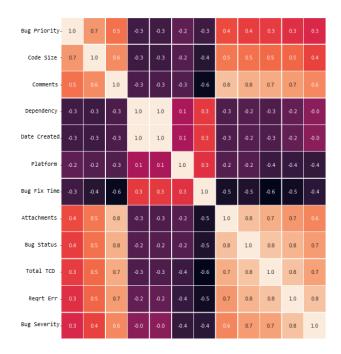
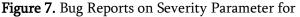


Figure 6. Correlation Graph for Most relevant Feature Selection

Table 1. Bug Attribute Description					
Attribute	Short Description				
* Severity	It is the Response Categorical				
	Variable This Indicates how severe				
	the problem is.				
Bug Id	The unique numeric id of a bug				
Priority	This field describes the importance				
,	and order in which a bug should be				
	fixed compared to other bugs. P1 is				
	considered the higher and P5 is the				
	lowest.				
Resolution	The resolution field indicates what				
	happened to this bugs				
Status	The status field indicates the				
	current state of bug				
	(New,Resolved,Progress)				
Number of	Bugs have comment added to them				
Comments	by user . #comments made to a bug				
	report				
Create Date	When the bug was field.				
Dependency	If this bug cannot be fixed unless				
	other bugs are fixed (depend on), or				
	this bug stops other bugs being				
	fixed (blocks) their number are				
	recorded here.				
Summery	A one-sentence summery of the				
	problem.				
Date of	When the bug was closed.				
close					
Keywords	The administrator can define				
	keywords which you can use to tag				
	and categorize bugs e.g. the Mozilla				
	project has keyword like crash and				
	regression.				
Version	The field define the version of the				
	software the bug was found in.				
CC List	A list of people who get mail when				
	the bug changes. #people in CC list				
Platform	These indicate the computing				
and OS	environment where the bug was				
Num 1 C	found.				
Number of	Number of Attachment for a bug.				
Attachment					
Bug Fix	Last resolved time-Opened time.				
Time	Time to fix a bug.				

Next, Stacking was performed by applying Rayleigh defect density on generating the mean probabilities of the classifiers hence further performance tuning led to the improved accuracy of the testing dataset as compared to the individual classifiers. Figures 7-9 depict the results of proposed MSRM model applied on 204545 bugs to depict the F1 Score.

	blocker	critical	major	normal	minor	trivial	enhancement	Total
e4	53	93	282	3075	\$2	15	193	3769
Equinox	257	434	1032	10215	357	101	1303	13699
Incubator		2	2	42	1	*	2	49
JDT	418	1304	3994	37999	3130	988	9255	57088
PDE	169	420	1328	11748	520	221	1939	16345
Platform	1532	3860	10383	76831	4370	1819	14800	11359
Total	2429	6113	17021	139910	8435	3145	27492	20454



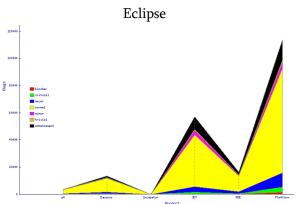


Figure 8. Severity Classification for Mozilla Product

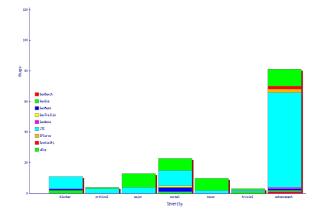


Figure 8. No. Of bugs Correctly classified for Bugzilla with Severity Prediction.

The final evaluation metric is to compute the error in prediction by the stacked regression Model(MSRM) as compared to the NN, LSVM and Linear regression Model.

Root mean squared error (RMSE): RMSE is a quadratic scoring rule that also measures the average magnitude of the error. It's the square root of the average of squared differences between prediction and actual observation.

RMSE =
$$\sqrt{\frac{1}{n} \sum_{j=1}^{n} (y_j - \hat{y}_j)^2}$$
.....(xiii)

The RMSE values as calculated on the bug dataset classification and prediction was

Table 2.	Comparative	Error	Estimates
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Model	RMSE Value
Neural Network	0.0184908700285
Linear SVM	0.0136835156595
Linear Regression	0.0115793611054
MetaStacked Regression	0.00989779285401

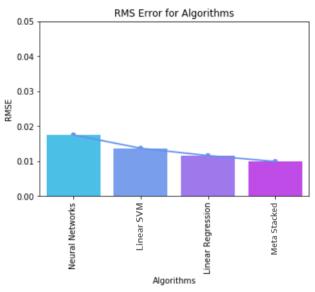


Figure 8. Comparative Predictive error of MSRM Model.

VI. CONCLUSION

It has been clearly demonstrated that Meta stacked regression analysis can be successfully applied to formulate a prediction model for bug classification and hence effort estimation. It is feasible to incorporate and implement defect prediction as part of software development process, particularly test process. The data collected has been tested on open source Projects with datasets (Mozilla, Eclipse, Bugzilla) and have scope for extension to other software development projects with their respective metrics. Future enhancements include adopting the MSRM model for web-based and component-based software data sets.

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